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| Notice of References Cited | Application/Control No. 10/601,701 | Applicant(s)/Patent Under Reexamination YEH ET AL. | |
| | Examiner Stanetta D. Isaac | Art Unit 2812 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| | A | US-6,689,647 | 02-2004 | Joo et al. | 438/151 |
| | B | US-6,100,119 | 08-2000 | Jang et al. | 438/151 |
| | C | US-5,589,406 | 12-1996 | Kato et al. | 438/164 |
| | D | US-2004/0026738 | 02-2004 | Hasegawa, Hisashi | 257/347 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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